

/ MOS FIELD EFFECT TRANSISTOR NP80N055CLE, NP80N055DLE, NP80N055ELE

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

These products are N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance

 $R_{\text{DS(on)1}}$ = 11 $m\Omega\,$ MAX. (Vgs = 10 V, Ip = 40 A)

 $R_{DS(on)2} = 13 \text{ m}\Omega$ MAX. (Vgs = 5 V, ID = 40 A)

- \bullet Low C_{iss} : C_{iss} = 2900 pF TYP.
- Built-in gate protection diode

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	Voss	55	V
Gate to Source Voltage	Vgss	±20	V
Drain Current (DC) Note1	ID(DC)	±80	Α
Drain Current (Pulse) Note2	D(pulse)	±200	Α
Total Power Dissipation (T _A = 25 °C)	Рт	1.8	W
Total Power Dissipation (Tc = 25 °C)	Рт	120	W
Single Avalanche Current Note3	las	45 / 30 / 10	Α
Single Avalanche Energy Note3	Eas	2.0 / 90 / 100	mJ
Channel Temperature	Tch	175	°C
Storage Temperature	T_{stg}	-55 to +175	°C

Notes 1. Calculated constant current according to MAX. allowable channel temperature.

- **2.** PW \leq 10 μ s, Duty cycle \leq 1 %
- 3. Starting $T_{ch} = 25 \, ^{\circ}\text{C}$, $R_G = 25 \, \Omega$, $V_{GS} = 20 \, V \rightarrow 0 \, V$ (see Figure 4.)

THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	1.25	°C/W
Channel to Ambient	Rth(ch-A)	83.3	°C/W

ORDERING INFORMATION

PART NUMBER	PACKAGE
NP80N055CLE	TO-220AB
NP80N055DLE	TO-262
NP80N055ELE	TO-263

(TO-220AB)



(TO-262)



TO-263)



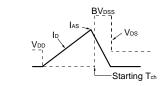
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ELECTRICAL CHARACTERISTICS (TA = 25 °C)

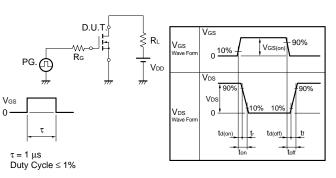
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 40 A		8.4	11	mΩ
	RDS(on)2	Vgs = 5 V, ID = 40 A		10.3	13	mΩ
	RDS(on)3	Vgs = 4.5 V, ID = 40 A		11.3	15	mΩ
Gate to Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	1.5	2.0	2.5	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 40 A	20	40		S
Drain Leakage Current	Ipss	V _{DS} = 55 V, V _{GS} = 0 V			10	μΑ
Gate to Source Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		2900	4400	pF
Output Capacitance	Coss			380	570	pF
Reverse Transfer Capacitance	Crss			170	310	pF
Turn-on Delay Time	td(on)	$I_D = 40 \text{ A}, V_{GS(on)} = 10 \text{ V}, V_{DD} = 28 \text{ V},$		22	48	ns
Rise Time	tr	$R_G = 1 \Omega$		10	25	ns
Turn-off Delay Time	td(off)			62	120	ns
Fall Time	tr			11	27	ns
Total Gate Charge 1	Q _{G1}	ID = 80 A, VDD = 44 V, VGS = 10 V		50	75	nC
Total Gate Charge 2	Q _{G2}	ID = 80 A, VDD = 44 V, VGS = 5 V		26	39	nC
Gate to Source Charge	Qgs			12		nC
Gate to Drain Charge	Q _{GD}			15		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 80 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	$I_F = 80 \text{ A}, \text{ Vgs} = 0 \text{ V}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		50		ns
Reverse Recovery Charge	Qrr]		100		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

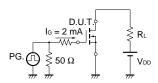
$R_{G} = 25 \Omega$ $V_{GS} = 20 \rightarrow 0 V$ $R_{G} = 25 \Omega$ V_{D} V_{D} V_{D}



TEST CIRCUIT 2 SWITCHING TIME



TEST CIRCUIT 3 GATE CHARGE



TYPICAL CHARACTERISTICS (T_A = 25°C)

Figure 1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

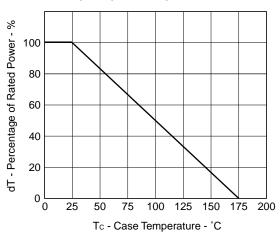


Figure 3. FORWARD BIAS SAFE OPERATING AREA

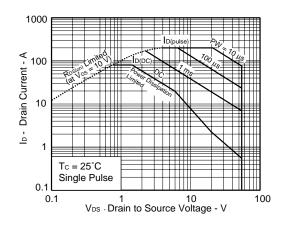


Figure2. TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

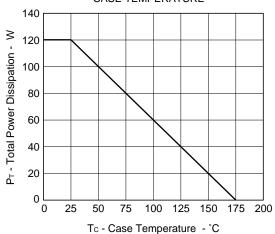
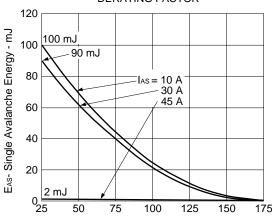


Figure4. SINGLE AVALANCHE ENERGY DERATING FACTOR



Starting Tch - Starting Channel Temperature - °C

Figure 5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

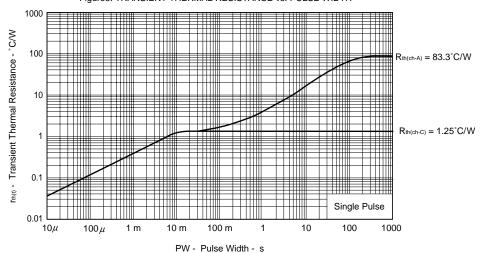


Figure 6. FORWARD TRANSFER CHARACTERISTICS

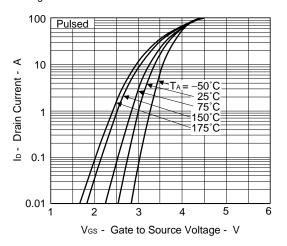
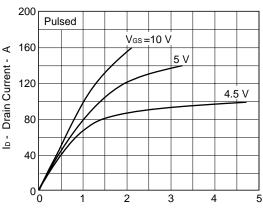


Figure 7. DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



V_{DS} - Drain to Source Voltage - V

Figure 8. FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

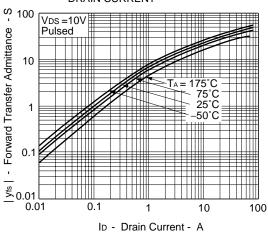


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

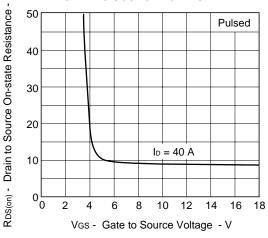


Figure 10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

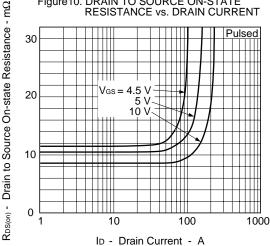
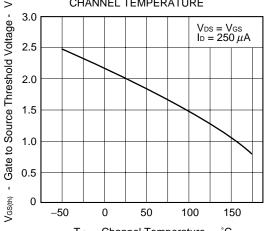
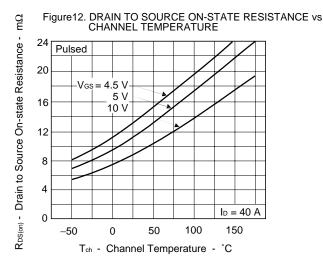
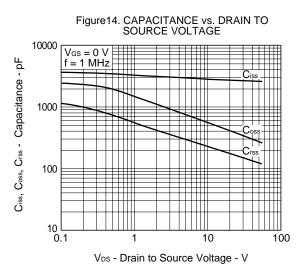


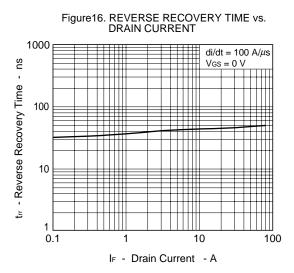
Figure 11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

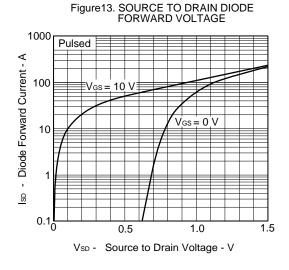


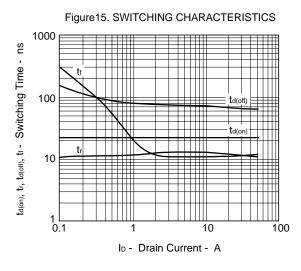
 T_ch - Channel Temperature - $^\circ\mathsf{C}$











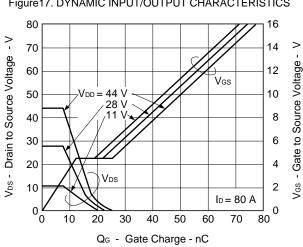
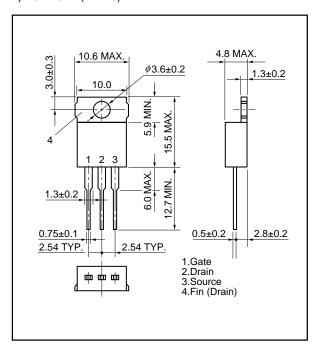


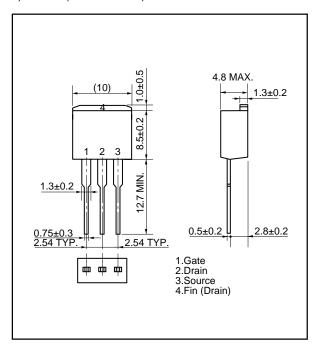
Figure 17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS

PACKAGE DRAWINGS (Unit: mm)

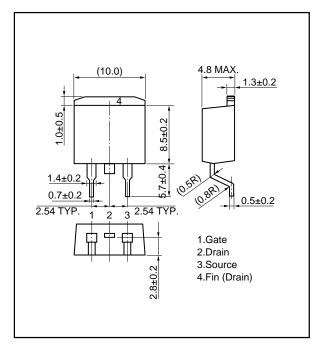
1) TO-220AB (MP-25)



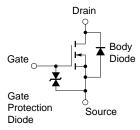
2) TO-262 (MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

[MEMO]

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